

The DAQ system has been tested and appears to be fully operational.
All the DAQ pcs behave normally
All VME, NIM and CAMAC crate work normally.
All the VME boards respond normally to the initialization process and some data has been taken with a pulser trigger.
The logic and distribution of the DAQ Trigger, the DAQ busy, the Start of Spill and the End of Spill signals appear normal.

Unfortunately, the High Voltage crate supplying the TOFs and KL has been found seriously damaged and had to be send back to the manufacturer for repair. This prevents us for testing the trigger logic system and the amplification/shaping and discrimination chain for the TOF and KL signals. However, the fact that no electronics module (VME or NIM) involved in the DAQ system has been damaged is a strong indication that the probability of founding a damaged module in the crates is small. The TOF and KL shapers will be tested manually on Tuesday the 22nd since they are critical, home made, items.

A test run is scheduled on Wednesday the 23rd with only GVA1, the CKOV and the PBM detectors read out.